

Search Notes

Application/Control No.

10/776,783

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

ASANO ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
252	79.1	1/4/2008	BT
252	79.4	1/4/2008	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using databases in EAST	1/4/2008	BT